PE C INFORMATION DISCLOSURE STATEMENT		Docket Number: 50019.0272US01	Application Number: 10/786,846	
O TO TOWN OF THE CONTRACT OF T	IN AN APPLICATION	Applicant: Qiang Luo		
	(Use several sheets if necessary)	Filing Date: 2/25/2004	Group Art Unit: Not Yet Assigned	

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EXAMINER INITIAL	DOCUMENT NO.	DATE	NAME	CLASS	SUBCLASS	FILING IF APPRO			
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						YES	NO		
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EXAMINER: Initial if reference considered, whether or not citation is in conformance with MPEP 609; draw line through citation if not in conformance and not considered. Include copy of this form for next communication to the Applicant.

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' FORM EKC-II		63,705 8	Any. Docker No. 89044PCW Customer No. 01333	_	Serial No. 10/786,846		
If AFTER the later date of the first office Action or 3 months from filing, use only with Rule 97(E) Certificate or Fee			Applicans: Qiang Luo				
INFORMATION DISCLOSURE STATEMENT BY APPLICANT (Use several sheets if necessary)			Filing Date 25 February 2004			Graup 2811	
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